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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/630,680	08/01/2000	Shinichi Imai	819-405	7497
•	90 08/29/2003			18
Eric J. Robinson		EXAMINER		
Nixon Peabody LLP Suite 800		-	AHMED, SHAMIM	
8180 Greensbor			ART UNIT	PAPER NUMBER
McLean, VA	22102		1765	
			DATE MAILED: 08/29/2003	

Please find below and/or attached an Office communication concerning this application or proceeding.

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	Applicati n No.	Applicant(s)	
•	09/630,680	IMAI, SHINICHI	
Office Action Summary	Examiner	Art Unit	
	Shamim Ahmed	1765	
The MAILING DATE of this communication	appears on the c ver shee	et with th correspondence address	
Peri d for Reply	EDI V IS SET TO EYDIRE	3 MONTH(S) FROM	
A SHORTENED STATUTORY PERIOD FOR RETHE MAILING DATE OF THIS COMMUNICATION - Extensions of time may be available under the provisions of 37 CF after SIX (6) MONTHS from the mailing date of this communication - If the period for reply specified above is less than thirty (30) days, and If NO period for reply is specified above, the maximum statutory period for reply within the set or extended period for reply will, by solution - Any reply received by the Office later than three months after the mearmed patent term adjustment. See 37 CFR 1.704(b).	DN. R 1.136(a). In no event, however, m n. a reply within the statutory minimum original apply and will expire SIX (6) tatute cause the application to become	ay a reply be timely filed of thirty (30) days will be considered timely. MONTHS from the mailing date of this communication. me ABANDONED (35 U.S.C. § 133).	
1) Responsive to communication(s) filed on	<u>04 June 2003</u> .		
	This action is non-final.		
3) Since this application is in condition for al closed in accordance with the practice un	lowance except for formal der <i>Ex parte Quayle</i> , 193	I matters, prosecution as to the merits is 5 C.D. 11, 453 O.G. 213.	:
Disp sition of Claims	-dina in the application		
4) ⊠ Claim(s) <u>1,3,4,6,9,10,12 and 19</u> is/are per			
4a) Of the above claim(s) is/are with	Idrawn from Consideration		
5)⊠ Claim(s) <u>19</u> is/are allowed.			
6)⊠ Claim(s) <u>1,3,4,6,10 and 12</u> is/are rejected.			
7) Claim(s) g is/are objected to.	nd/or election requiremen	t	
8) Claim(s) are subject to restriction a Application Papers		•	
9)☐ The specification is objected to by the Exam			-
10)☐ The drawing(s) filed on is/are: a)☐ :			
Applicant may not request that any objection			
11) The proposed drawing correction filed on _		JE disapproved by the Examiner.	
If approved, corrected drawings are required 12) The oath or declaration is objected to by the			
,—	C Examinor.		
Priority under 35 U.S.C. §§ 119 and 120 13) Acknowledgment is made of a claim for for	reign priority under 35 H :	S.C. & 119(a)-(d) or (f).	
a) ☐ All b) ☐ Some * c) ☐ None of:	reign priority under do o.	3.0.3(2) (2)	
1. Certified copies of the priority docu	ments have been received	1.	
2. Certified copies of the priority docu			
		been received in this National Stage	
application from the Internation * See the attached detailed Office action for	al Bureau (PCT Rule 17.2	(a)).	
14) ☐ Acknowledgment is made of a claim for dor	mestic priority under 35 U.	S.C. § 119(e) (to a provisional application))-
 a) The translation of the foreign languag 15) Acknowledgment is made of a claim for do 	e provisional application hestic priority under 35 U	nas been received. .S.C. §§ 120 and/or 121.	
Attachment(s)			
1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-94 3) Information Disclosure Statement(s) (PTO-1449) Paper N	.8) 5) 🔲 Not	erview Summary (PTO-413) Paper No(s) ice of Informal Patent Application (PTO-152) er:	

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DETAILED ACTION

Response to Arguments

1. Applicant's arguments with respect to claims 1,3-4,6-7,9-10 and 12 have been considered but are moot in view of the new ground(s) of rejection.

Applicants argue that Inazawa et al does not teach the etching selection ratio of the silicon dioxide/resist is increased.

In response, examiner states that applicant's argument is more specific than the claims because the selection ratio between the silicon oxide/resist is not claimed.

Applicants also argue that examiner should provide evidence to support the official notice taken on the previous office action.

In response, examiner states that the argument is moot upon canceling the claim 7 and furthermore, the limitation of the canceled claim is incorporated in the newly added claim 19, which is now allowed.

Claim Objections

2. Claim 9 is objected to under 37 CFR 1.75(c), as being of improper dependent form for failing to further limit the subject matter of a previous claim. Applicant is required to cancel the claim(s), or amend the claim(s) to place the claim(s) in proper dependent form, or rewrite the claim(s) in independent form. Claim 9 is now depends on a cancel-based claim 13.

Remarks

The newly added claim 13 is renumbered as claim 19 according to the Rule 126.

Claim Rejections - 35 USC § 103

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3. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

- (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 4. Claims 1,3-4, and 6 are rejected under 35 U.S.C. 103(a) as being unpatentable over Inazawa et al (5,595,627) in view of Zhu et al (6,297,163).

Inazawa et al disclose a plasma etching process, wherein a silicon dioxide layer is etched over a substrate in which a resist pattern is also been formed and the etching is performed using a fluorocarbon gas such as C_4F_8 (col.2, lines 16-20 and col.6, lines 8-23).

Inazawa et al fail to teach the introduction of a fluorocarbon gas contains at least one of C_4F_6 , C_5F_8 and C_6F_6 gases.

However, Zhu et al teach an etching process, wherein silicon dioxide is etched using flurocarbon gases such as C_5F_8 , CF_4 , C_4F_8 , etc. (col.5, lines 9-12 and col.6, lines 66-col.7, line1).

Therefore, it would have been obvious to one skilled in the art at the time of claimed invention to combine Zhu et al's teaching into Inazawa et al's process because both the C_5F_8 and C_4F_8 gases are functionally equivalent and would perform the same as the claimed invention as taught by Zhu et al.

Inazawa et al also disclose that residence time of the processing gas is determined and Controlled in a predetermined range.

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Further more, Inazawa et al teach that the value of the residence time dependence on the basis of the target value of the etching ratio (col.7, lines 18-25 and col.8, lines 14-24).

Inazawa et al fail to teach the exact value of the residence time.

However, it would have been obvious to one skill in the art at the time of claimed invention to optimize the specific time for the etching in order to maintain a proper etching section ratio, since it has been held that where the general conditions of a claim are disclosed in the prior art, discovering the optimum or workable ranges involves only routine skill in the art. *In re Aller*, 105 USPQ 233.

As to claim 4, Inazawa et al teach that pressure of the processing chamber, flow rate of the fluorocarbon gas and the voltage is controlled by a controller section (col.8, lines 36-42).

Inazawa et al remain silent about controlling P x w_0 / Q at 0.8x 10^4 sec. W/m³ or less than $8x10^4$ sec.W/m³.

It would have been obvious to one skill in the art at the time of claimed invention to optimize the same for effective etching ratio, since it has been held that where the general conditions of a claim are disclosed in the prior art, discovering the optimum or workable ranges involves only routine skill in the art. *In re Aller*, 105 USPQ 233.

5. Claims 10 and 12 are rejected under 35 U.S.C. 103(a) as being unpatentable over Nguyen et al (5,244,730) in view of Mountsier et al (6,184,572).

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Nguyen et al disclose a plasma process, wherein an organic film is deposited on a substrate by introducing a fluorocarbon gas of C_4F_8 (col.3, lines 37-49).

As to claim 10, Nguyen et al fail to disclose the fluorocarbon gas could be at least one of C_4F_6 , C_5F_8 and C_6F_6 gases.

However, Mountsier et al teach that hexafluorobenzene (C_6F_6) is a beneficial fluorocarbon gas over a commonly used fluorocarbon gas such as C_4F_8 to deposit organic film.

Mountsier et al also disclose that the resulting film has better capability to withstand in high temperature (col.3, lines 6-23).

Therefore, it would have been obvious to one skilled in the art at the time of claimed invention to combine Mountsier et al's teaching into Nguyen et al's process in order to deposit an organic film, which exhibit greater thermal stability as taught by Mountsier et al.

Nguyen et al disclose that power density is of the process is typically maintain at the range of 0.05 to about 0.4 W per cm² along with the residence time (col.4, lines 49-59).

Nguyen et al also disclose that pressure, flow rate and the residence time of the fluorocarbon gas is maintained at about 0.9 seconds (col.3 lines 37-49 and col.4, lines 14-17), wherein the residence time is generally expressed by a simple equation: residence time = capacity of the processing chamber x pressure / supply rate of the processing gas, which is supported by Inazawa et al (col.7, lines 17-22 of the patent 5,595,627).

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Nguyen et al remain silent about controlling P x w₀ / Q at 0.8x 10⁴ sec.W/m³.

However, it would have been obvious to one skill in the art at the time of claimed invention to optimize the same for efficient controlling the deposition rate, since it has been held that where the general conditions of a claim are disclosed in the prior art, discovering the optimum or workable ranges involves only routine skill in the art. *In re Boesch*, 617 F.2d 272,, 205 USPQ 215 (CCPA 1980).

As to claim 12, Nguyen et al teach that a pump controls the pressure of the chamber and also the flow rate of the gas is controlled by a valve (col.4, lines 31-36 and lines 45-48).

Allowable Subject Matter

- 6. Claim 19 is allowable over prior art.
- 7. The following is a statement of reasons for the indication of allowable subject matter: The prior art does not teach an etching/deposition process, wherein residence time of the first and the second fluorocarbon gas for the first and the second plasma, respectively is controlled at two different value as the context of claim 19.

Conclusion

8. Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within

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TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of

the advisory action. In no event, however, will the statutory period for reply expire later

than SIX MONTHS from the date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Shamim Ahmed whose telephone number is (703) 305-1929. The examiner can normally be reached on M-Thu (7:00-5:30) Every Friday Off.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Nadine G Norton can be reached on (703) 305-2667. The fax phone number for the organization where this application or proceeding is assigned is (703) 872-9306.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703) 308-0661.

Shamim Ahmed Examiner Art Unit 1765

SA

NADINE G. NORTON PRIMARY EXAMINER